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# Try our New Full-text Search Prototype

- 1) Enter a single keyword, phrase, or Boolean expression. Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes,

Example: optical <and> (fiber <or> fibre) <in> ti

- 3) Limit the results by selecting Search Options.
- 4) Click Search. See Search Examples

((call\* <near/1> admission\* <near/1> control\*) or cac\*) and (time\*stamp\* or (tim\* <near/2> stamp\*))



Note: This function returns plural and suffixed forms of the keyword(s).

Search operators: <and> <or> <not> <in> More

Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) More

## Search Options: Select publication types: ☑ IEEE Journals IEE Journals

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